

**Notice of References Cited**

Application/Control No.

10/622,458

Applicant(s)/Patent Under  
Reexamination  
YOON ET AL.

Examiner

Malcolm D. Cribbs

Art Unit

2115

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,805,139	09-1998	Uehara, Keiichi	345/156
*	B	US-2002/0180704	12-2002	Rudd, Michael L.	345/168
*	C	US-5,511,184	04-1996	Lin, Pei-Hu	710/261
*	D	US-5,642,318	06-1997	Knaack et al.	365/201
*	E	US-2002/0091850	07-2002	Perholtz et al.	709/231
*	F	US-6,101,608	08-2000	Schmidt et al.	726/2
*	G	US-2005/0206355	09-2005	Leith et al.	323/274
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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